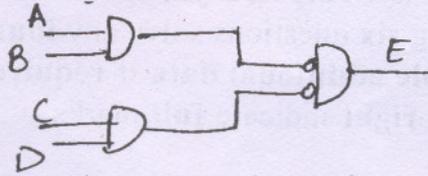




3. (a) Explain the path sensitization method of fault detection and location. What are the advantages and disadvantages of the path sensitization method? Use this method for the following circuit :— 10



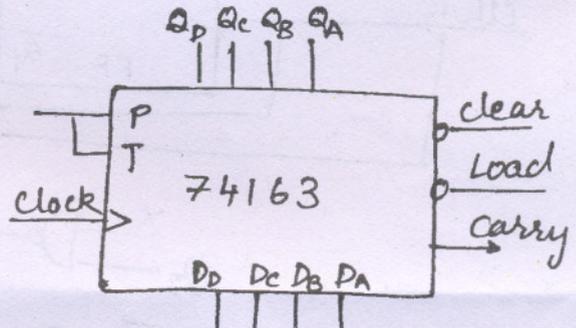
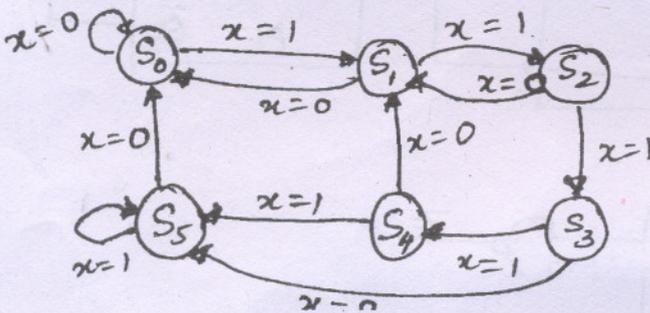
- (b) Implement the following sets of functions using a decoder and some gates. Design the logic for minimum chip count :— 10

$$F_1(A, B, C) = \Sigma m(2, 3, 5, 7)$$

$$F_2(A, B, C) = \Sigma m(1, 2, 3, 4, 5, 7)$$

$$F_3(A, B, C) = \Sigma m(0, 1, 2, 5)$$

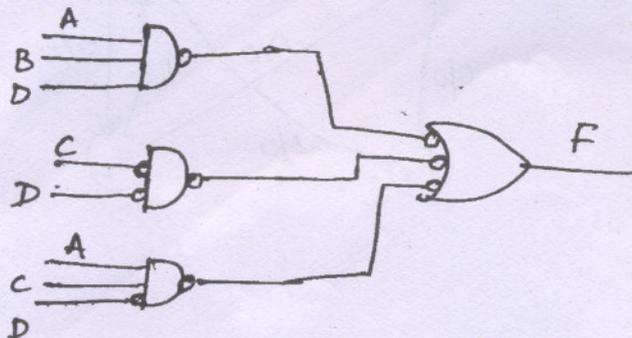
4. State diagram for a sequential network is shown below. Realise the network using IC 74163 and PLA. Use the order  $Q_D, Q_C, Q_B, Q_A$  for the state variables. Operation of 74163 is also shown :— 20



Clear	Load	PT	$Q_D$	$Q_C$	$Q_B$	$Q_A$	
0	x	x	0	0	0	0	(clear)
1	0	x	$D_D$	$D_C$	$D_B$	$D_A$	(load)
1	1	0	$Q_D$	$Q_C$	$Q_B$	$Q_A$	(No change)
1	1	1	Present state + 1				(Increment count)

5. (a) The incoming serial data is to be detected in overlapping mode for the sequence. . . . 10110. . . . The output z is asserted high when the sequence is received. Draw the state diagram and realize the logic using D-Flip Flop and gates. 12

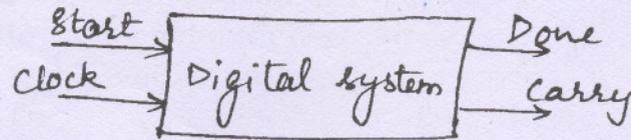
- (b) For the circuit given below determine the number of logic hazards. What product terms are necessary to eliminate these logic hazards? Write the logic hazard free function for the circuit 8



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6. Two four bit numbers are loaded in two shift registers x and y which are part of a digital system. It is desired to design this system which will work as a four bit serial adder. The input output signals are shown in the schematic diagram. 20



On receiving 'start' it will begin the serial operation of adding the numbers in the registers x and y. After the operation is over the sum will be stored in the register X, the carry will be available as an output and it will output 'Done'. Make a functional partition diagram of the system and MDS diagram of its controller. Design the controller.

7. Consider the following faults of the D-F/F circuit of figure  $a_0, b_0, c_0, e_1, f_1$  where a, b, c, e, f 20 denote the location of the faults in the circuit and the subscript 0 and 1 denote s-a-0 and s-a-1 faults respectively—

- Determine the undetectable and indistinguishable faults.
- Find the optimum tests sequence to detect these faults.

